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Dr. Kate A. Remley

Metrology for Wireless Systems Group, National Institute
of Standards and Technology (NIST), USA

**“Bringing Precision to Measurements for Millimeter-
wave 5G Wireless: Conducted and free-field
modulated-signal measurements”**

Datum: 13.10.2017
Zeit: 14:00-16:00 Uhr
Ort: Lehrstuhl für Hochfrequenztechnik (Prof. Eibert),
Technische Universität München TUM, Gebäude N5,
Elektrotechnik, 4. Obergeschoss, Raum 512 (Seminarraum)
Theresienstr. 90, 80333 München

Datum: 17.10.2017
Zeit: 15:00-17:00 Uhr
Ort: Institut für Theoretische Elektrotechnik TET
(Prof. Schuster), **Hamburg University of Technology TUHH**,
Räumlichkeiten werden noch bekannt gegeben



EMC Distinguished Lecture by Dr. Kate A. Remley

Bringing Precision to Measurements for Millimeter-wave 5G Wireless: Conducted and free-field modulated-signal measurements

At millimeter-wave frequencies and for wide modulation bandwidths, the hardware performance of both modulated-signal sources and vector receivers becomes increasingly nonideal. These nonidealities make test and validation of devices, circuits and systems not only more important, but also more difficult. This is especially true because future systems will likely push the limits of modulation complexity and bandwidth to increase data throughput. We will discuss calibration and measurement techniques to correct millimeter-wave modulated-signal measurements illustrating that traditional assumptions at microwave frequencies may not be adequate at millimeter-wave frequencies.

Kate A. Remley is the leader of the Metrology for Wireless Systems Group at NIST, where her research activities include development of calibrated measurements for microwave and millimeter-wave wireless systems and developing standardized test methods for RF equipment used by the wireless community. Dr. Remley was the recipient of the Department of Commerce Bronze and Silver Medals, an ARFTG Best Paper Award, and is a member of the Oregon State University Academy of Distinguished Engineers. She was the Chair of the MTT-11 Technical Committee on Microwave Measurements from 2008 - 2010 and the Editor-in-Chief of IEEE Microwave Magazine from 2009 - 2011, and is currently the Chair of the MTT Fellow Nominating Committee. She is a Distinguished Lecturer for the IEEE EMC Society (2016-2018).